

**Notice of References Cited**

Application/Control No.

10/530,559

Applicant(s)/Patent Under  
Reexamination  
MIURA ET AL.

Examiner

QIAN YANG

Art Unit

2625

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0140260	07-2003	Kizawa et al.	713/300
*	B	US-2002/0178387	11-2002	Theron, John	713/300
*	C	US-2002/0149789	10-2002	Okazawa, Takashi	358/1.14
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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